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# **Digital X-ray portable scanner based on monolithic semi-insulating GaAs detectors: *General description and first “quantum” images***

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# OUTLINE

## ➤ MOTIVATION

- GaAs material properties
- Line scan operation

## ➤ **DETECTORS:** LEC SI GaAs strip line in edge on configuration

- Characterization of tested detectors
- Etched trenches in strip line technology
- Tests of parallel strip connection
- Microfocus beam tests

## ➤ SCANNER CONSTRUCTION

## ➤ **FIRST IMAGES** OBTAINED WITH X-ray SCANNER

## ➤ CONCLUSIONS

# MOTIVATION

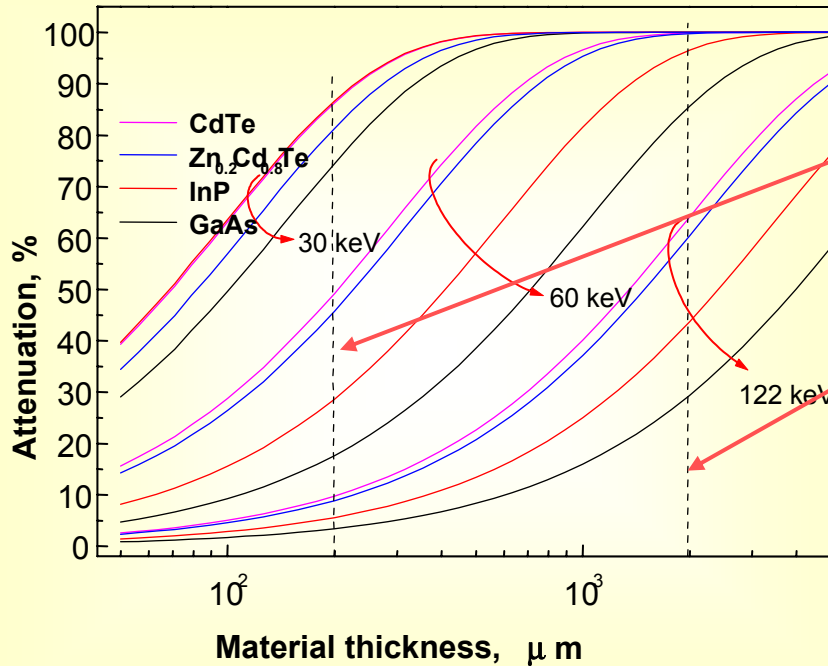
## GaAs MATERIAL PROPERTIES

- ✓ Radiation hardness
- ✓ Low cost
- ✓ Fast
- ✓ Wide band gap – operation at RT
- ✓ Highly developed technology processing
- ✓ Easily commercially available

## LINE SCANNING TECHNIQUE IN RADIOGRAFIC IMAGING

- ✓ Technical simplest solution
- ✓ Low cost
- ✓ Useful for fast testing of detector applicability in X-ray imaging
- ✓ High quality of X-ray image (good scattered rejection)
- ✓ Useful for many industrial and even medical applications

# CHOICE OF GaAs DETECTOR – X-ray SOURCE GEOMETRY



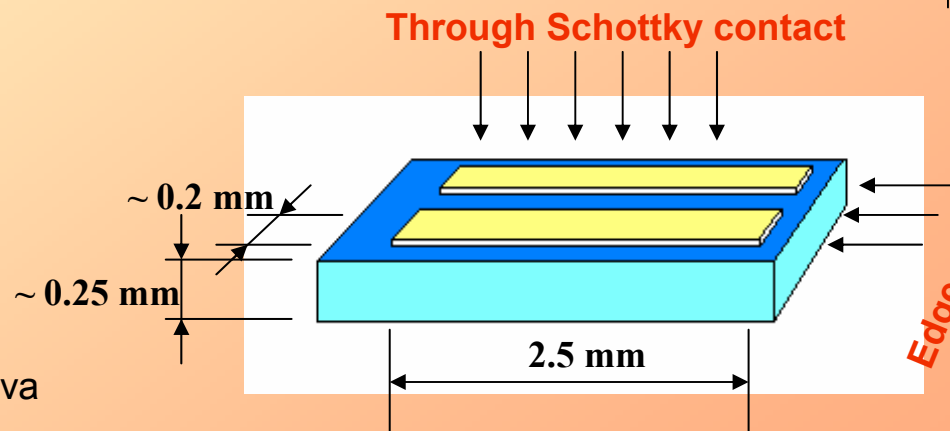
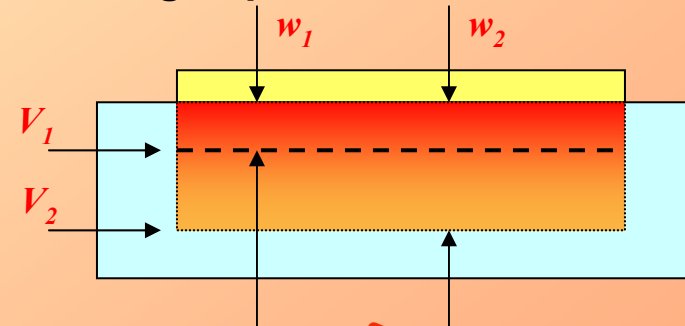
*Two modes of detector irradiation:*

## Through Schottky contact:

- absorption length 0.25 mm
- 25% @ 60 keV

## Edge on configuration:

- absorption length 2.5 mm
- 85% @ 60 keV,
- high spatial resolution



# CHARACTERIZATION OF INVESTIGATED STRIP LINE DETECTOR

Substrate: 250  $\mu\text{m}$  of **bulk undoped LEC SI GaAs** - (CMK Ltd, Žarnovica, Slovakia)  
with resistivity of  $5.2 \times 10^7 \Omega\text{cm}$  and Hall mobility of  $5200 - 5800 \text{ cm}^2\text{V}^{-1}\text{s}^{-1}$

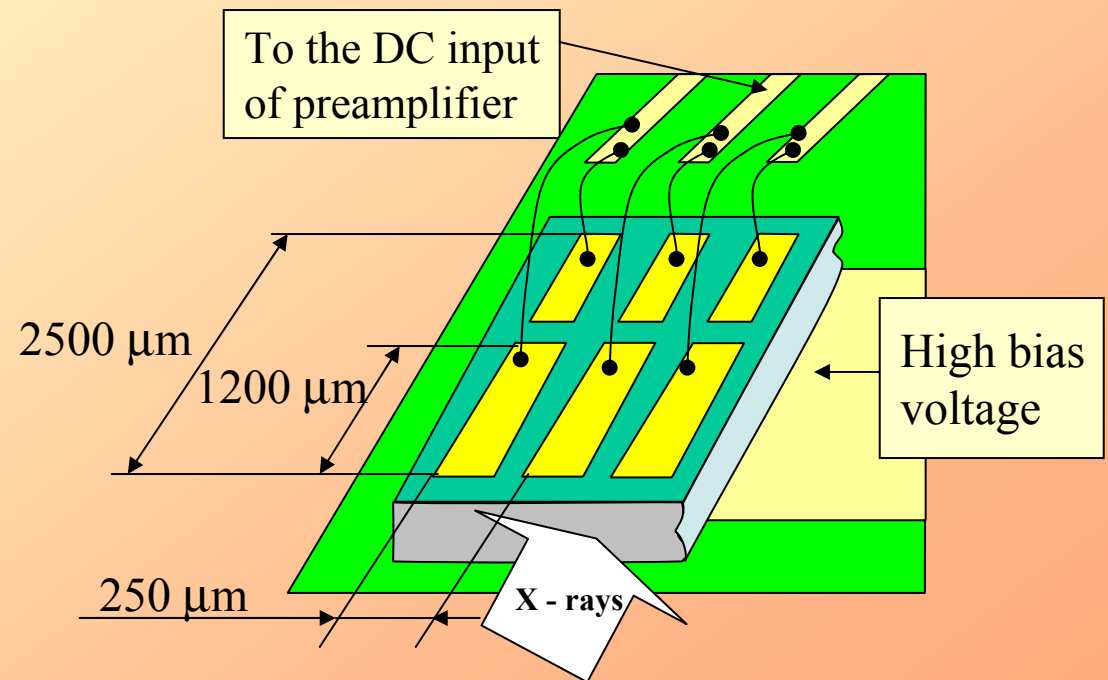
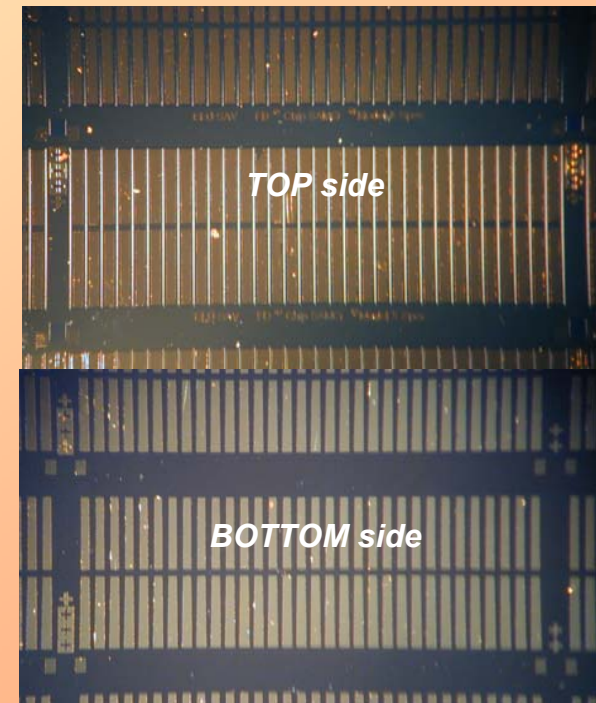
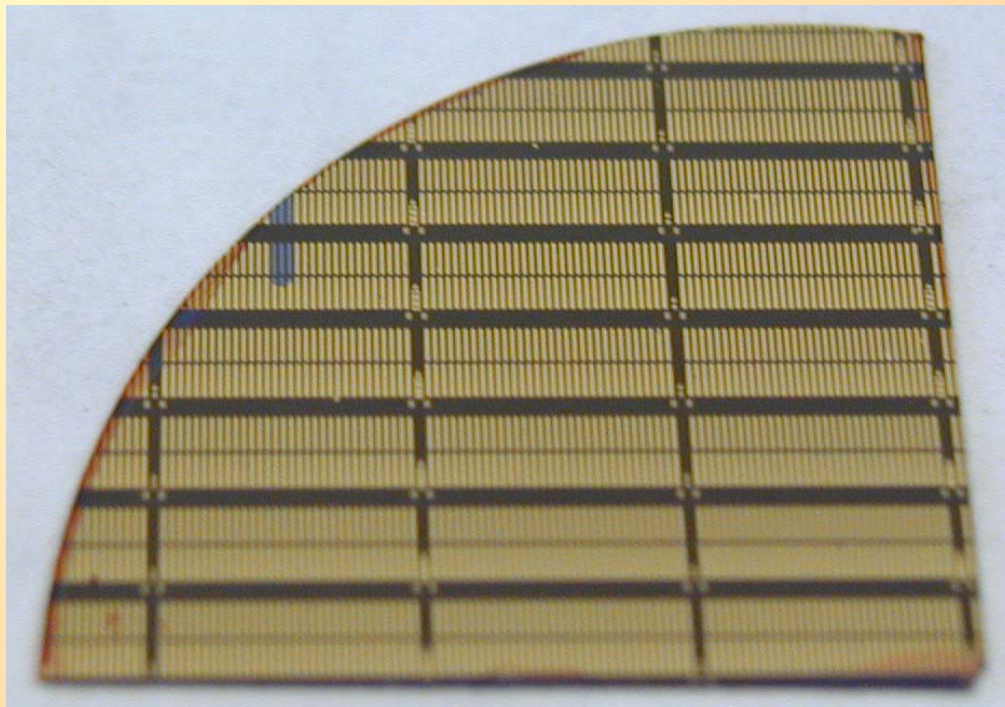


Photo and schematic view of monolithic strip line detector segment

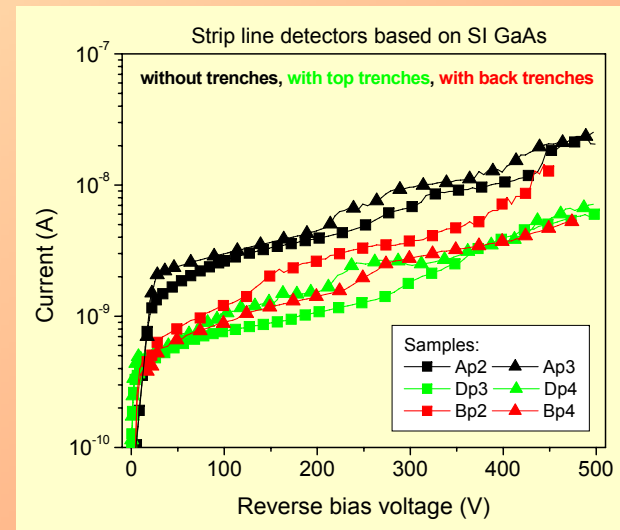
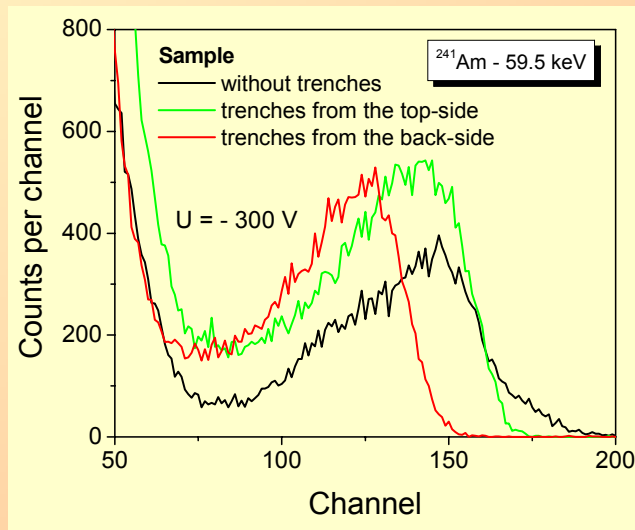
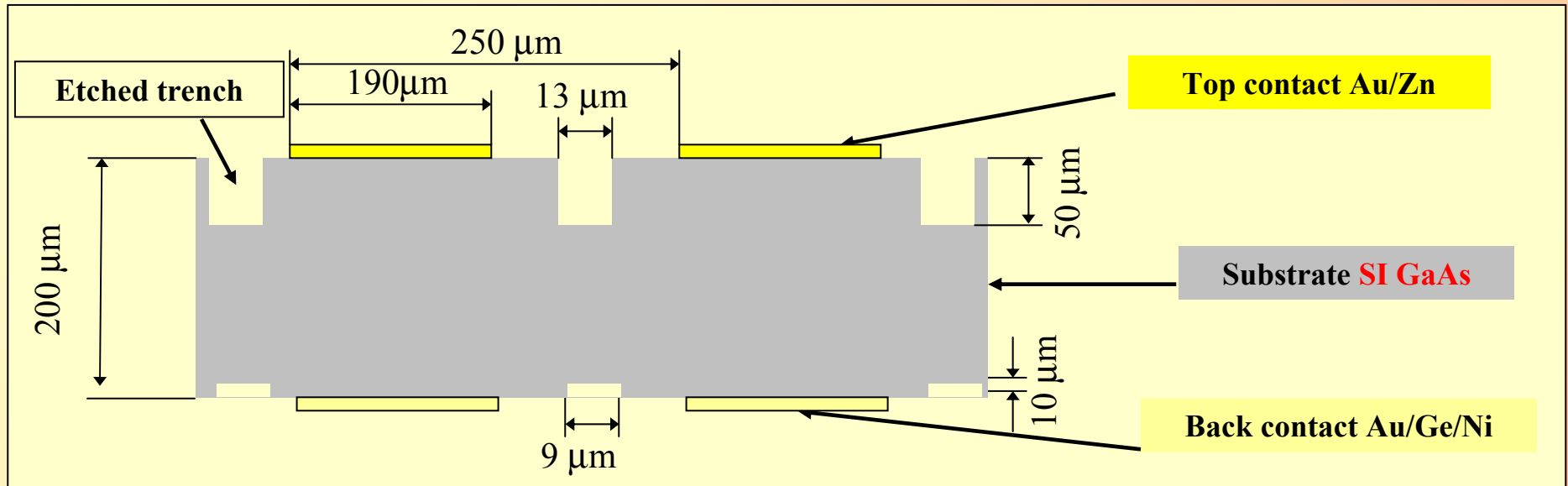
## SI GaAs strip line detector: SAMO-XS

Number of strips in line	Pitch (mm)	Absorption length (mm)	Size of line detector (mm)	Effective absorption volume of strip (mm <sup>3</sup> )	Maximum thickness of detector field (mm)
<b>32</b>	<b>0.25</b>	<b>1.20</b> <b>0.25</b>	<b>8 x 3.5</b>	<b>0.10</b> <b>0.18</b>	<b>0.2 – 0.3</b>



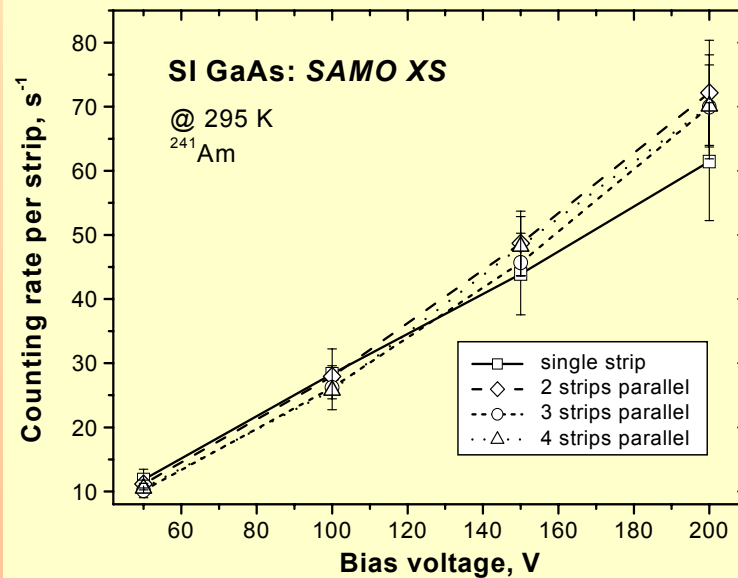
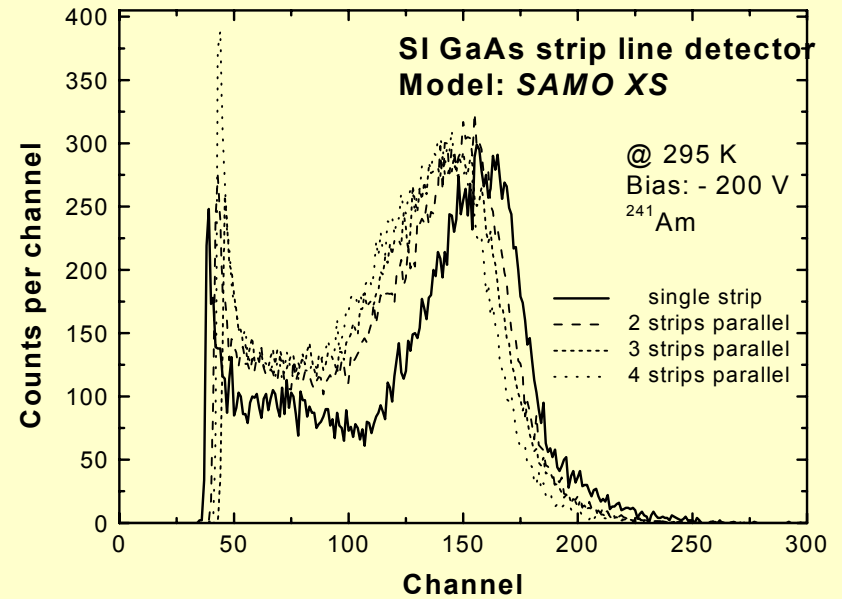
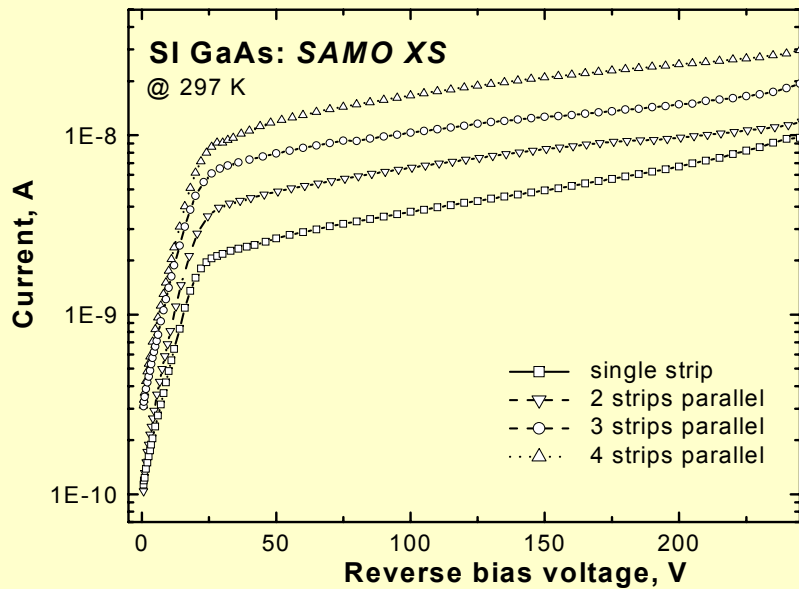
# ETCHED TRENCHES IN TECHNOLOGY OF STRIP LINE DETECTORS

Trenches creation: RIE (reactive ion etching) technique, additional photolithographic masking (frame of 8  $\mu\text{m}$ )



Andrea Perdochova

# ELECTRIC AND DETECTION PROPERTIES OF PARALLELLY CONNECTED STRIPS

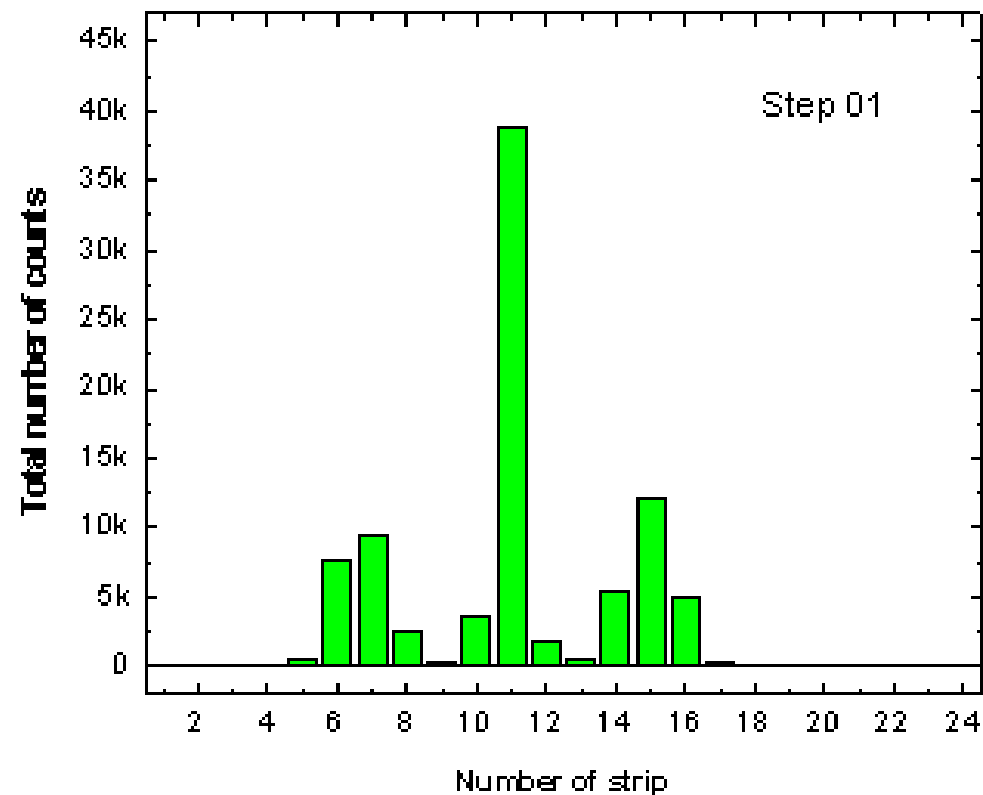




## MICROFOCUS BEAM TEST OF CROSS-TALK BETWEEN NEIGHBOURING STRIP LINE DETECTORS

- X-ray tube: 60 kV, 50 mA
- X-ray beam:  $\varnothing$  250  $\mu\text{m}$
- Step: 25  $\mu\text{m}$  starting from 11<sup>th</sup> to 13<sup>th</sup> strip
- Time of measurement: 1 s

RESULT: Negligible cross-talk of strips in line determined

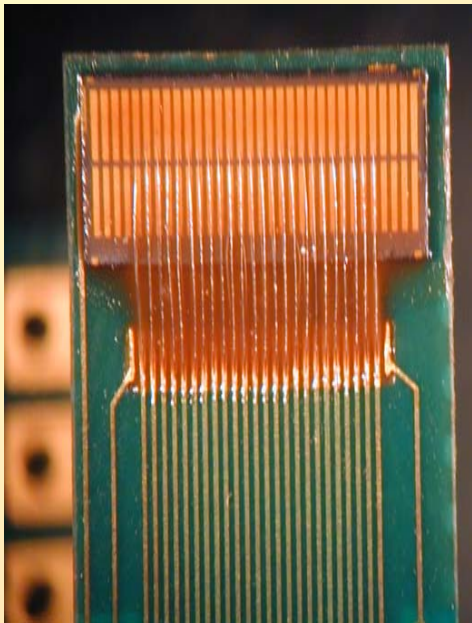


Andrea Perdochova

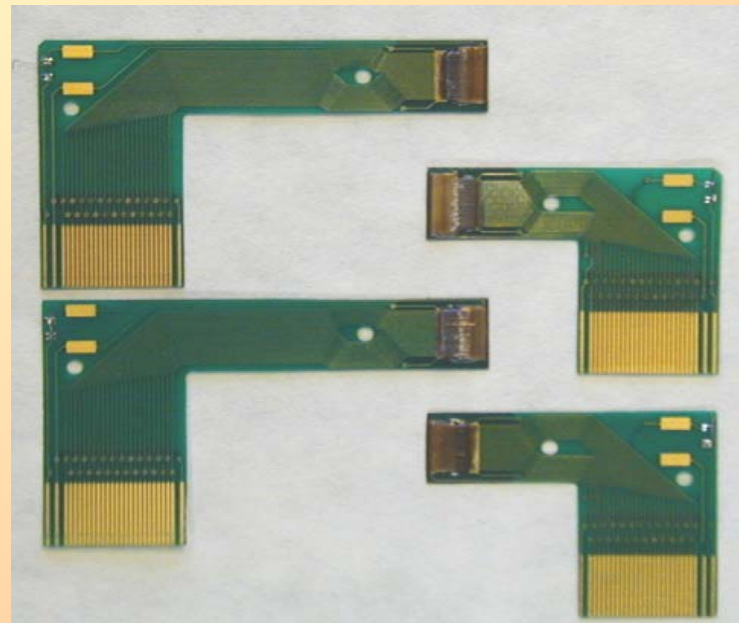
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Authors are acknowledged to Fraunhofer Institut für Zerstörungsfreie Prüfverfahren EADQ Dresden for enabling the experiments

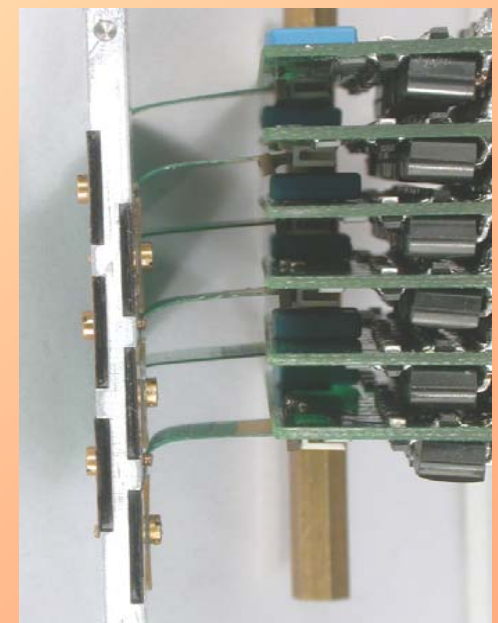
## SI GaAs STRIP LINE DETECTOR ASSEMBLY



Detail of chip bonded on PCB



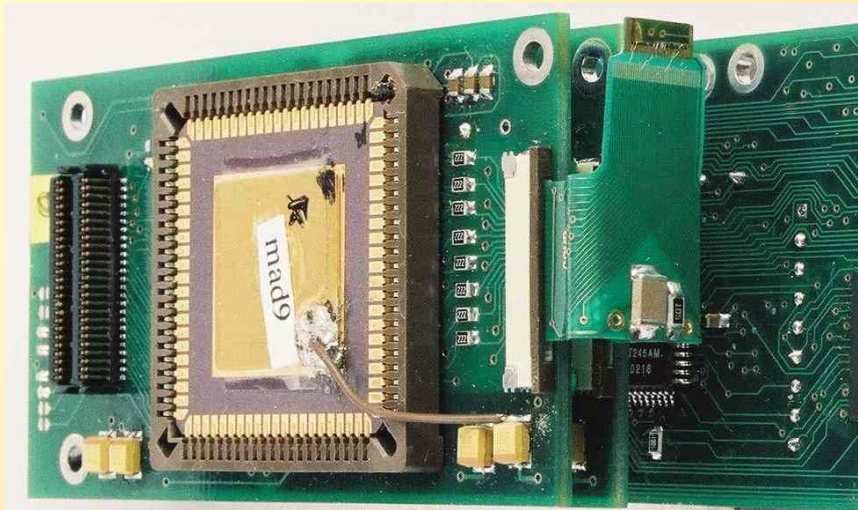
Mounted on 0.25 mm thick PCB holder



Test prototype of detection line

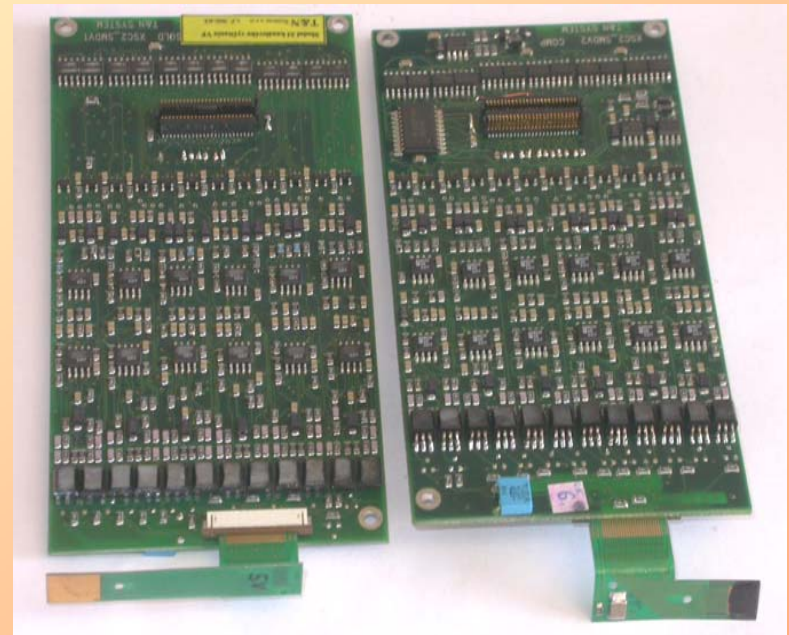
# PROGRESS IN READOUT ELECTRONICS

**PROTOTYPE CONCEPT:  
Based on VLSI readout circuit  
(IWORID 2003)**



- Prototype series
- Technical problems
- High cost

**FINAL DESIGN OF F-E READOUT:  
SMD assembled PCB**

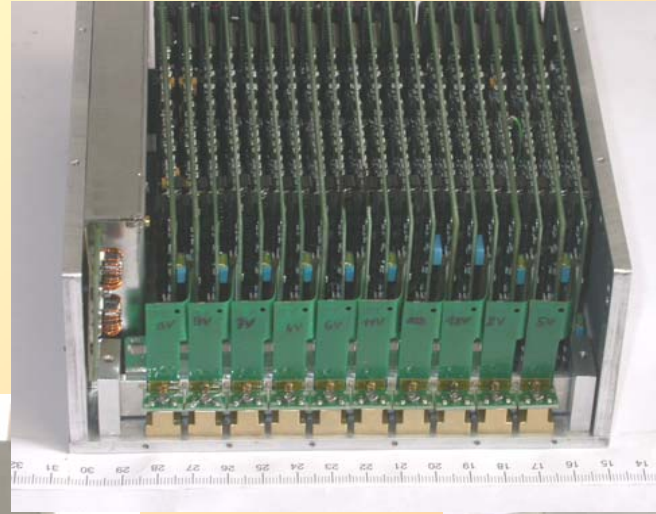


- Low cost per channel
- Simple possibility in modification
- Optimized for used chip holder

## FINAL CONSTRUCTION OF X-ray SCANNER BASED ON SAMO XS STRIP LINE DETECTORS

➤ 480 strip SI GaAs detectors in line 12 cm long (pitch 0.25 mm)

➤ 20 readout analogue cards, each with 24 readout channels



**View of opened analog scanner part with cooling system (in front)**

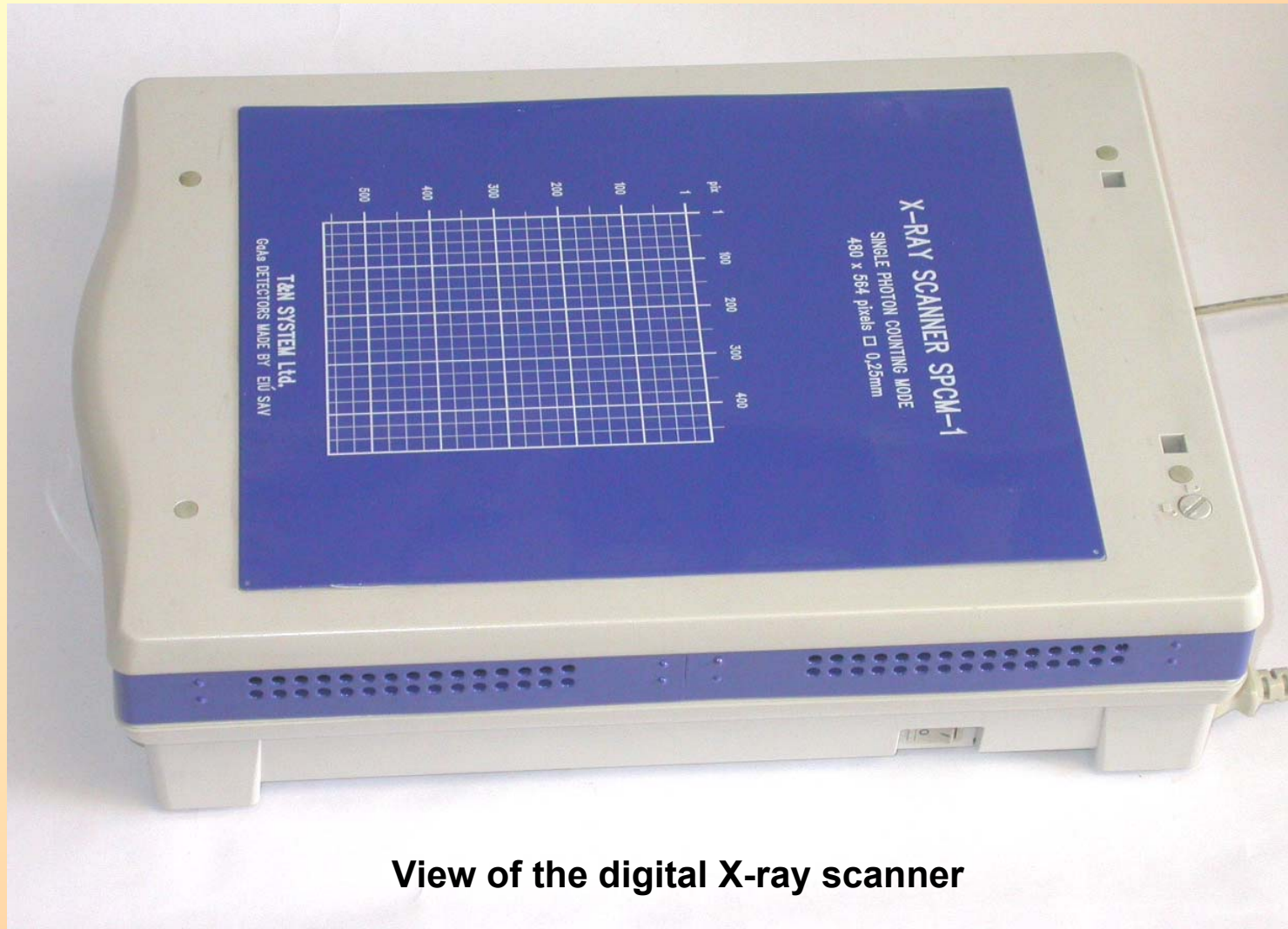


**Detection unit of scanner in cover with X positioning motion system up to 14 cm (in 564 (250  $\mu\text{m}$ ) or 1650 (85  $\mu\text{m}$ ) steps)**

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# THE FIRST DIGITAL X-ray SCANNER

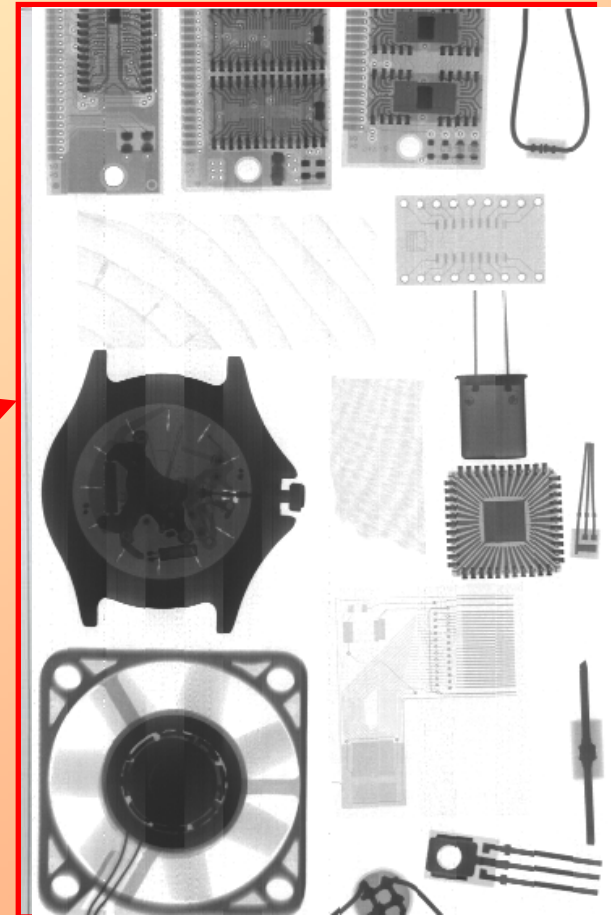
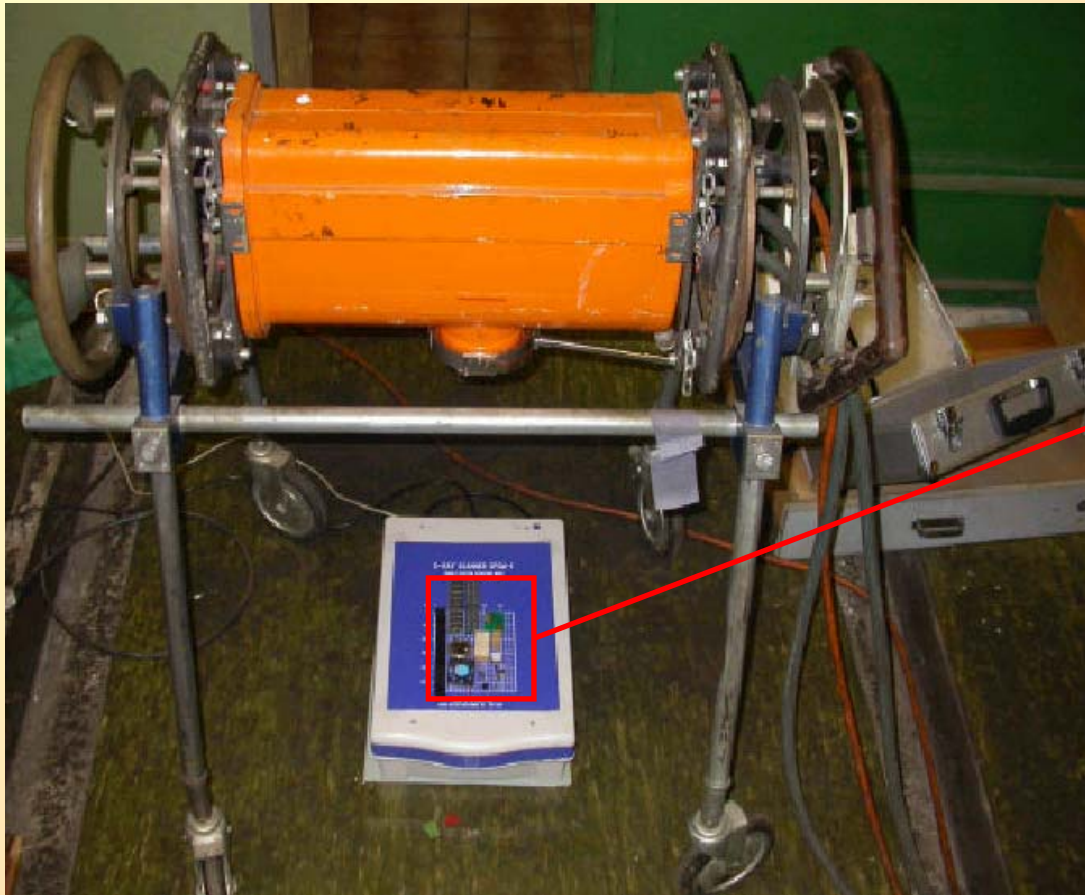
*based on bulk SI GaAs radiation detectors working in quantum mode*



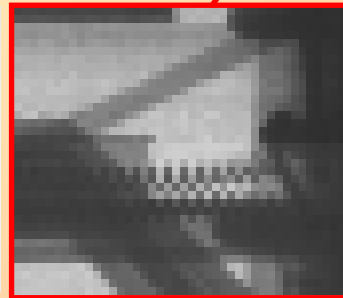
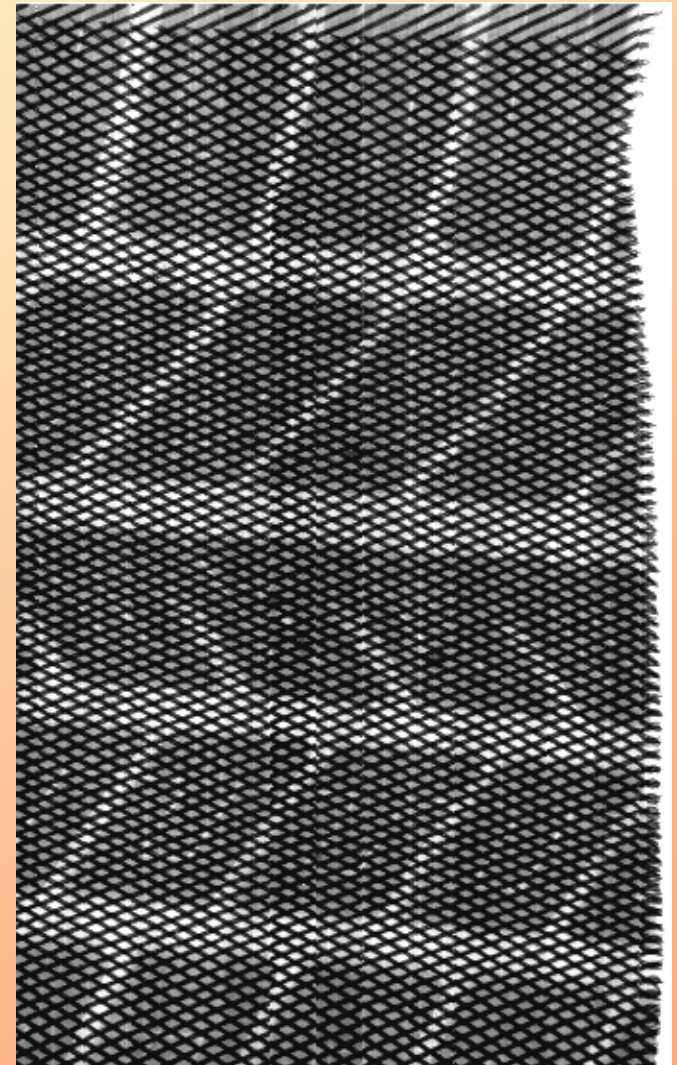
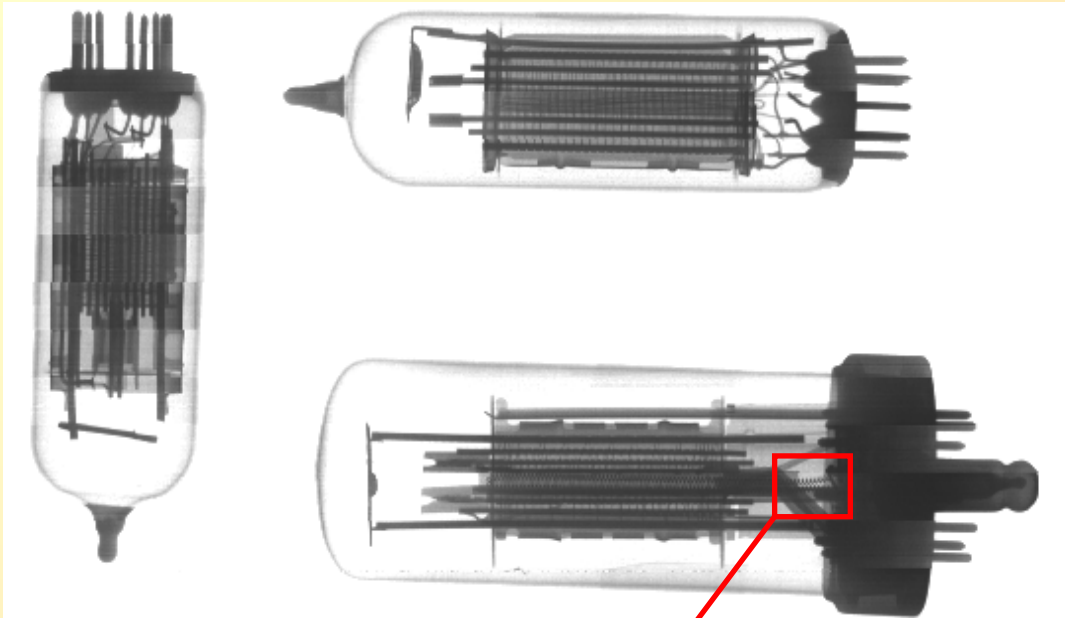
**View of the digital X-ray scanner**

# FIRST IMAGES OBTAINED WITH X-RAY SCANNER EXPERIMENT

X-ray tube: 70 kV, 8 mA, 1 s per line



## PHOTOS AND X-ray IMAGES



X-ray tube: 70 kV, 8 mA, 0.05 s per line

# CONCLUSIONS

- **DETECTOR**

*Successful realization of line strip detectors based on bulk undoped SI GaAs (CMK Ltd., Žarnovica).*

- **CHIP MOUNTING**

*Flexible PCB holders with direct connection through micro-connector.*

- **READOUT ELECTRONICS**

*Front-end readout modul fabricated using progressive SMD technology with automatic assembling of electronic devices (24 channels, equivalent noise charge  $< 400 e^- rms$ , maximum readout rate  $10^5 s^{-1}$ , memory of each modul, common threshold, USB connection to PC).*

- **X-POSITIONNING MOTION SYSTEM**

*Minimum adjustable step of 0.085 mm.*

- **DEVELOPED CONTROLLING COMMUNICATION AND IMAGING SOFTWARE**

*3 corrections including:*

- *normalisation of background counting inhomogenities*
- *compensation of instabilities in X-ray tube flux*
- *compensation of differences in collection of even and odd 24 strip chips (due to diverging photons)*

- **FUTURE PLANS**

- *detail study of imaging performance of the developed X-ray scanner*
- *improvement of line arrangement*
- *increasing spatial resolution using finer step of the line*
- *implementaion of collimated X-ray source in the scanning system...*



# GOLDEN AWARD OF 36<sup>th</sup> FAIR INCHEBA, BRATISLAVA 2004

**INCHEBA**  
EKOTECHNIKA

36. medzinárodný chemický veľtrh  
11. medzinárodná výstava ochrany životného prostredia  
2. výstava laboratórnej techniky  
8. výstava meracej a regulačnej techniky  
14. medzinárodný gumársky veľtrh  
2. výstava získavania, využitia a ochrany vody  
Rozvoj regiónov miest a obcí

Generálny riaditeľ a.s. INCHEBA  
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udelili  
ocenenie

**ZLATÁ  
INCHEBA**

Exponát: Monolitický GaAs detektor  
rtg. zariadenia a jeho aplikácia  
v digitálnom rtg. skeneri  
Výrobca: Elektrotechnický ústav SAV,  
T&N System, s.r.o.  
Vystavovateľ: Elektrotechnický ústav SAV

INCHEBA  
a.s.  
BRATISLAVA

Generálny riaditeľ a.s. INCHEBA

Predseda súťažnej poroty

Andrea Perdochova